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AMENDMENT TRANSMITTAL LETTER (Larg Applicant(s): Kiyohito MUKAI, et al.				Docket No. L8462.03118			
Application No.	Filing Date	Examiner		Customer I	No.	Group Art Un	it Confirmation No.
10/715,119,	November 18, 2003	N. Doan		52989		2825	2755
Invention: FEHCONDUCTOR DEVICE LAYOUR INSPECTION METHOD  NOV 0 8 2006							
COMMISSIONER FOR PATENTS:  Transmitted herewith is an amendment in the above-identified application							
Transmitted herewith is an amendment in the above-identified application.							
The fee has been calculated and is transmitted as shown below.							
CLAIMS AS AMENDED							
	CLAIMS REMAINING	HIGHEST #	NUMB	ER EXTRA	DATE		ADDITIONAL
	AFTER AMENDMENT	PREV. PAID FOR	CLAIMS	PRESENT		RATE	FEE
TOTAL CLAIMS	1 -	20 =		0	x	\$50.00	\$0.00
INDEP. CLAIMS	1 -	12 =		0	x	\$200.00	\$0.00
Multiple Dependent Claims (check if applicable)							\$0.00
TOTAL ADDITIONAL FEE FOR THIS AMENDMENT \$0.0							\$0.00
No additional fee is required for amendment.  Please charge Deposit Account No. in the amount of A check in the amount of to cover the filing fee is enclosed.  The Director is hereby authorized to charge payment of the following fees associated with this communication or credit any overpayment to Deposit Account 19-4375 Any additional filing fees required under 37 C.F.R. 1.16. Any patent application processing fees under 37 CFR 1.17.  Payment by credit card. Form PTO-2038.  WARNING: Information on this form may become public. Credit card information should not be included an this form. Provide credit card information and authorization on PTO-2038.  Dated: November 8, 2006  I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail in an envelope addressed to "Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450" [37 CFR 1.8(a)] on							
Tel: 202-785-0100 Fax: 202-408-5200  CC:				(Date)  Signature of Person Mailing Correspondence			

Typed or Printed Name of Person Mailing Correspondence



In re the Application of

Inventor: Kiyohito MUKAI et al. Group Art Unit: 2825

Appln. No.: 10/715,119 Examiner: N. M. Doan

Filed: November 18, 2003

For: SEMICONDUCTOR DEVICE LAYOUT INSPECTION METHOD

## AMENDMENT UNDER 37 CFR § 1.111

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

In response to the Office Action dated August 8, 2006, please amend the above-captioned application as follows: